

Notice of References Cited	Application/Control No. 10/525,146		Applicant(s)/Patent Under Reexamination KIM ET AL.	
	Examiner Pablo N. Tran		Art Unit 2618	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2007/0042794	02-2007	Fischer, Patrick	455/466
*	B	US-2006/0274780	12-2006	Walsh et al.	370/458
*	C	US-2006/0146858	07-2006	Kim, Myeong-Cheol	370/432
*	D	US-2006/0072516	04-2006	Jeong et al.	370/335
*	E	US-2006/0040655	02-2006	Kim, Myeong-Cheol	455/426.1
*	F	US-2005/0249141	11-2005	Lee et al.	370/312
*	G	US-2005/0153715	07-2005	Hwang et al.	455/458
*	H	US-2005/0118992	06-2005	Jeong et al.	455/422.1
*	I	US-2005/0111395	05-2005	Hwang et al.	370/313
*	J	US-2004/0029596	02-2004	Kim et al.	455/458
*	K	US-2004/0180675	09-2004	Choi et al.	455/458
*	L	US-2004/0229605	11-2004	Hwang et al.	455/426.1
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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